

Atacama Large Millimeter Array

Band 6 Cartridge Database Design Description

FEND-40.02.06.00-138-A-DSN

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Change Record

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1. Introduction

1.1. Purpose

This document describes the design for the Band 6 Cartridge Configuration Database. This database holds information about the particular parts used to construct each Band 6 cartridge along with the electrical settings required to operate the cartridge.

1.2. Scope

Band 6 Test Systems measure data and format it according to [AD01]. That test and configuration data are delivered along with Band 6 Cartridge assemblies to the Front End Integration Center. The mixer and amplifier test systems measure and characterize cartridge components which are then integrated into a cartridge assembly and measured on the Band 6 Cartridge Test System. The result is variety of data items, each of which is keyed to a particular component or cartridge assembly.

For a given cartridge, the relevant data falls into the following broad categories:

- 1. **Parts used during assembly:** The part numbers and serial numbers of subassemblies that comprise each complete Band 6 Cartridge.
- 2. **Operational parameters:** The information needed to operate the cartridge and its subassemblies within the context of the ALMA installation. This information will be duplicated in the ALMA Archive area for operational parameters when that portion of the Archive becomes available.
- 3. **Amplifier test results:** The results of Cold IF Amplifier testing on the Band 6 Amplifier Test System.
- 4. **Mixer test results:** The results of SIS Mixer-Preamp block testing on the Band 6 Mixer Test System.
- 5. **Cartridge test results:** The full results of testing a cartridge assembly on the Band 6 Cartridge Test System, including items required for the cartridge acceptance report and additional data not required for the report, giving a full history of the testing performed on the cartridge test system.

1.3. Applicable documents

The following documents are part of this document to the extent specified herein. If not explicitly stated otherwise, the latest issue of the document is valid.

Table 1: Applicable Document List			
Reference	Document Title	ALMA Doc. Number	
[AD01]	Cartridge Data Formats for Delivery to the Front End Integration Centers	FEND-40.09.03.00-032-A-DSN	

1.4. Reference documents

The following documents contain additional information.



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Table 2: Reference Document List		
Reference	Document Title	ALMA Doc. Number

1.5. Acronyms

A list of the acronyms used in this document is given below.

ALMA <u>A</u>tacama <u>L</u>arge <u>M</u>illimeter <u>A</u>rray

Database

DBMS Database Management System

FE Front End

FEIC Front End Integration Center

FETMS Front End Test and Measurement System

IF <u>Intermediate Frequency</u>

LO Local Oscillator

NRAO <u>National Radio Astronomy Observatory</u>

RF Radio Frequency

TMS Test and Measurement System WCA Warm Cartridge Assembly

2. <u>Database Design Decisions</u>

2.1. An instance of MySQL server will be the main repository at each site.

The Band 6 Cartridge Database will reside on the same MySQL server as the North American FEIC database. This server is operated and maintained by the CV-Computing group. Backup and other maintenance of the server will be carried out by that group.

The target server version is to be MySQL 4.1, revision 18 or later. MySQL 5.0 may be considered if it is shown to possess a clear advantage.

2.2. Especially high performance is not required.

The database will ultimately contain millions of test data records, but will only require simultaneous use by less than 10 users. This is firmly within the capabilities of a modern medium-performance DBMS and does not call for dedicated hardware.

2.3. Moderate concurrency of access is required

The tasks which will access the database simultaneously are discussed in the detailed design section of this document. Essentially they are:

- 1. inserting cartridge configuration and operational parameter data;
- 2. creating test data at the Band6 Amplifier, Mixer, or Cartridge Test Systems; and
- 3. up to about 5 users viewing and occasionally modifying data from workstations.



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2.4. Data will be inserted and used by the test system software.

The most active creator and consumer of data in the database will be the Band 6 test system software. There may be two or more test system applications operating simultaneously.

2.5. Raw data will be stored with no calibration or post-processing applied.

All data measured by the test systems will be stored as returned from the instrument. The stored data shall include the result of any calibrations applied by the instrument to the data. Separate procedures, either automatic or initiated by client workstation software, will perform any additional calibration or post-processing on the data. Thus transformed, the data may be stored again in the database for subsequent display, reporting, or export. Data stored after such transformation does not replace the original raw data.

2.6. Data may be viewed and modified by workstation client software.

Data shall be gathered, tagged by the test system software, and then scanned for exceptions or anomalies away from the main test system, as needed.

2.7. Data format will be consistant with format required for data delivery.

Operation and test data required with cartridge delivery will be inserted into the FEIC Database as specified in [AD01]. An important requirement is that the data not require excessive transformation to conform to data delivery requirements described in [AD01]. It shall be a straightforward matter to match up the data as-delivered with its copy in the Band 6 Cartridge database.



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3. Detailed design of the database

3.1. Relational schema for Cartridge assembly configuration

Figure 1 shows the database tables that hold assembly configuration and operating parameters for cartridges, mixers, and preamplifiers. A subset of the information contained in these tables is deliverable as specified in [AD01]. To simplify the delivery process, the database configuration established for the FEIC is used as the template for this design, although some modifications and additions have been made to allow for tracking of more information required within the Band 6 group.

All tables include a primary key value defined as a unique auto-incrementing integer. Additionally each table contains a timestamp column called "TS." (This name was chosen because "timestamp" in any capitalization is a reserved word in some SQL implementations, notably MS Access). Common field abbreviations are "SN" for serial number and "PO" for purchase order number. The former is the number assigned by the project and/or cartridge manufacturer. The latter is purchase order number assigned to the item when it was purchased. Each table which corresponds to a physical assembly in the cartridge has a "Notes" column where any notes relevant to a given assembly may be placed.

Several of the tables include a field called TS_Removed. This field is used for recording the date and time when a record no longer represents the components actually installed in the cartridge or its subassembly. Rather than delete or change that record, the TS_Removed field contains the timestamp when the record became deprecated. For example, when a particular configuration of ColdCarts is no longer used for active testing because a mixer has been replaced, a new record will be created containing the new configuration and the old record will be retained for historical purposes. The old record's TS_Removed field will contain the date and time that the record became historical and the Notes field in the relevant table should also be updated with information about why the mixer was replaced.

The FEIC database doesn't include a separate mixer-preamp table and Figure 2 shows the mapping between the ColdCarts table in the FEIC database [AD01] and the MxrPreampAssys table in Figure 1.



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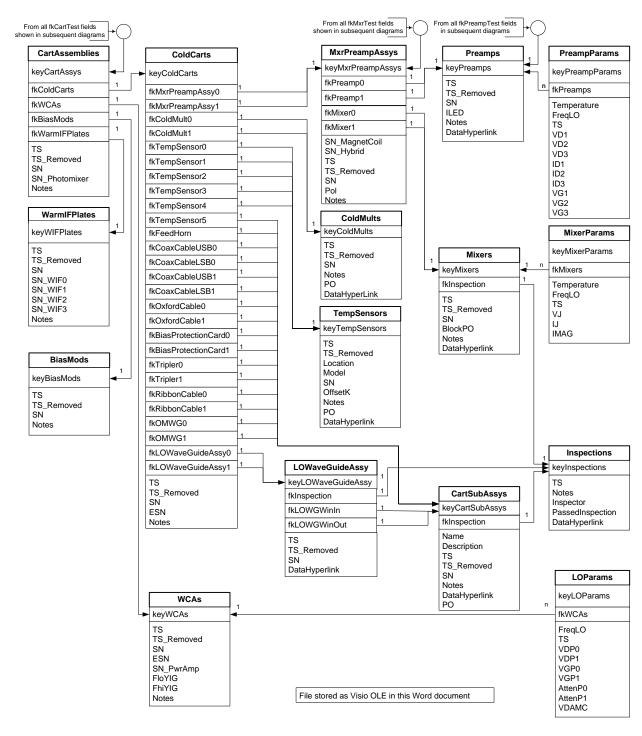
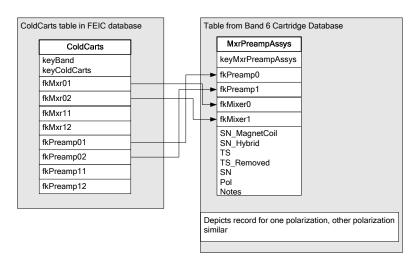


Figure 1: Cartridge Assembly Configuration Database Schema



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Figure 2: Mapping between ColdCarts table in the FEIC database and MxrPreapAssys table in Figure 1

3.1.1. Table CartAssemblies

Table CartAssemblies contains the configuration of which cold cartridges, WCAs, bias modules, warm IF plates, and photo-mixers are matched up with one another. The record with the most recent time stamp (TS) shall be interpreted as the full cartridge assembly as-delivered.

3.1.2. Table WarmIFPlates

Table WarmIFPlates gives the configuration of warm IF amplifiers and cables installed in a warm IF amplifier assembly. Though these are installed in the WCA, it makes more sense from the point of view of configuration history maintenance and test data delivery to associate them with the CartAssemblies. If a warm IF plate is removed or modified, the date and time removed is put in the TS_Removed field in tables WarmIFPlates and table CartAssemblies.



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3.1.3. Table BiasMods

Table BiasMods gives the serial numbers and notes about the cold cartridge bias module. These are also associated with a record in table CartAssemblies. If a bias module is removed, the date and time removed is put in the TS_Removed field of tables BiasMods and CartAssemblies.

3.1.4. Table WCAs

The child table wcas contains information about each Warm Cartridge Assembly that doesn't vary with LO frequency. Each record in wcas corresponds to a unique Warm Cartridge Assembly. A child table to wcas is the table Loparams, which holds frequency-dependent information about the WCA, such as the nominal power amplifier drain voltages and the attenuation settings. The foreign key fkwcas in the Loparams table provides the necessary mapping of many records in Loparams to a single record in wcas. When a WCA is removed, the date and time removed is put in the Ts_Removed field of table wcas and Table CartAssemblies also is given a new record with the Ts_Removed field in that table likewise updated.

3.1.5. <u>Table ColdCarts</u>

Table coldcarts in Figure 1 contains the serial number assigned to a cold cartridge and the configuration of which mixer-preamp assemblies, cold multipliers, temperature sensors, LO Waveguide assemblies, and other various subassemblies are matched up in a cold cartridge.

When a cold cartridge subassembly is removed, the TS_Removed field in ColdCarts as well as the TS_Removed field in CartAssemblies must be updated. When a cold cartridge subassembly is replaced, a new ColdCarts record will be inserted that has the same serial number and same foreign keys of unchanged items, but an updated foreign key referencing the newly-installed subassembly. A new record in the CartAssemblies table will also have to be inserted that has an updated foreign key referencing the most recent ColdCarts record. This method of updating records preserves the entire history of a cartridge assembly and all its components.

3.1.6. Table ColdMults

Child table ColdMults holds details about the two cold multipliers installed in each cartridge.

3.1.7. Table MxrPreampAssys

The table MXXPreampAssys provides the relationship between a cold cartridge and a mixer-preamp block, which includes two component mixers in each mixer block, two preamps, a hybrid and a magnet coil. A mixer-preamp assembly is designed for a particular polarization, and therefore the table contains a Pol field. The polarization on which a block is installed is also



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evident from in the ColdCarts table where fkmxrPreampAssy0 refers to the block on Pol 0 and fkmxrPreampAssy1 refers to the block on Pol 1. This table allows for the properties of a given mixer-preamp block to be determined even before it is assigned to a cold cartridge.

3.1.8. Table Mixers

- A. The table Mixers holds information about component mixers and the blocks in which they are installed. It also links a set of pumped and un-pumped component mixer I-V parameters. Pumped I-V parameters vary with LO frequency and physical temperature and are used in cartridge configuration and operation. The data identifying the mixer is stored in the Mixers table and the data which varies with LO is stored in the MixerParams table. Each row in the latter table contains a foreign key with values for fkMixers which matches a corresponding keyMixers value in the Mixers table.
- **B.** This table includes a foreign key referencing a record in the Inspections table. This links each mixer to information about when it was inspected, by whom, whether or not it passed inspection and a hyperlink to any inspection data recorded.

3.1.9. Table Preamps

Similarly, table Preamps holds the relationship between cold amplifiers and the mixer-preamp block in which they are installed. Each record in PreampParams contains foreign key field data in fkPreamps that matches Preamps. Each record in Preamps may be associated with a set of PreampParams records that define the preamp parameters.

This table includes a foreign key referencing a record in the Inspections table. This links each amplifier to valuable information about when it was inspected, by whom, whether or not it passed inspection and a hyperlink to any inspection data recorded.

3.1.10. Table TempSensors

Table TempSensors contains the temperature offsets at the liquid Helium boiling point (4.2K) which are applied to each temperature sensor integrated into a given cartridge. That is, when the sensor is dipped in LHe, if the indicated temperature is 4.3K, then +0.1K is entered as the offset for that sensor. ColdCarts contains five foreign keys into TempSensors because there are 5 temperature sensors installed in each cartridge. The locations assigned to fkTempSensor0 ... fkTempSensor4 are 110K stage, 15K stage, 4K stage, Pol 0 mixer, and Pol 1 mixer, respectively.

Temperature sensor calibration data is located in its own table because it is measured separately from mixer and preamp data.

This table also includes a PO field to store the purchase order number under which a temperature sensor was ordered.



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3.1.11. Table LOWaveGuideAssys

The table LOWaveGuideAssys documents the relationship between a cold cartridge and the LO waveguide assembly which includes two LO waveguide windows. A LO waveguide assembly is designed for a particular polarization in the cold cartridge and therefore, polarization information is stored in the ColdCarts table where fkloWaveGuideAssy0 refers to LO waveguide installed on Polarization 0 and fkloWaveGuideAssy1 refers to Polarization 1.

Waveguide window details are handled with foreign keys fklowgwinIn for the inner waveguide window and fklowgwinOut for the outer waveguide window in the CartSubAssys table.

This table allows for the properties of a given mixer-preamp block to be determined even before it is assigned to a cold cartridge.

3.1.12. Table CartSubAssys

The table CartSubAssys gives the relationship between a cold cartridge and its various subassemblies and provides the necessary fields to store records for the following types of components:

- 1. Feed Horns
- 2. Coax Cables
- 3. Triplers
- 4. Waveguide windows
- 5. Ribbon Cables
- 6. Over-Moded Wave Guides

The Name and Description field identify the type of component and its description or model number. For example: Name = 'Temperature Sensor' Description = 'Lakeshore DT-670C-SD'.

This table includes a foreign key referencing a record in the Inspections table. This links each subassembly to valuable information about when it was inspected, by whom, whether or not it passed inspection and a hyperlink to any inspection data recorded.

This table allows for the properties of a given subassembly to be determined even before it is assigned to a cold cartridge.

This table also includes a PO field to store the purchase order number under which a component was ordered or to identify a batch to which it belongs.

3.2. Relational schema for test data

3.2.1. Tracking software versions



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Software programs and versions used to collect or transform test data will be tracked using two tables, SoftwareVersions and SoftwarePrograms. For each software program used on a test system to collect or manipulate data in the database, a record will be placed in the SoftwarePrograms table. For each new version of a program released a new record will be placed in the SoftwareVersions table. The SoftwareVersions table contains a reference to the SoftwareProgram to which it applies. Sets of measurement data can use these tables to link a set of measured data to the software used to collect it.

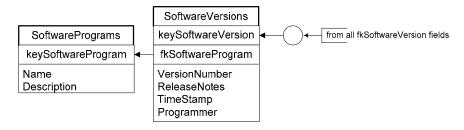


Figure 3: Software Version Tacking

3.2.2. Cartridge Assembly Test Data

Figure 4 illustrates the CartTests table, along with helper tables TestTypes, CartTestErrors, EnvConditions, and NotesCartTests. These tables provide the structure for recording the information gathered for any of a variety of tests performed on a cartridge assembly. Prior to data collection, test system software will insert a new record in CartTests. During a measurement, data records will be stored in other tables specific to the measurement being performing, but linked back to the CartTests record to which the data set belongs. Test system software can use the helper tables to record errors that occur during a measurement and log environmental conditions before, during, and/or after a measurement. The NotesCartTests table allows multiple notes to be associated with a particular CartTest.



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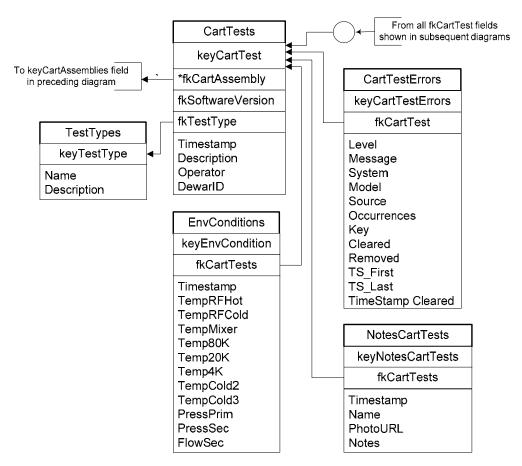


Figure 4: Cartridge Assembly Test Data

3.2.2.1. Cartridge Assembly Noise Temperature Test Data

Raw data collected during a noise temperature test on a cartridge assembly will be stored in the NT_Data table. It contains a reference to the NT_Calc_Data table which houses all calculated values. Records in the NT_Calc_Data table will be inserted as a post-processing procedure rather than during a measurement. These tables are illustrated in Figure 5 with an asterisk '*' indicating the fields required for data delivery to the FEIC database for noise temperature measurements.



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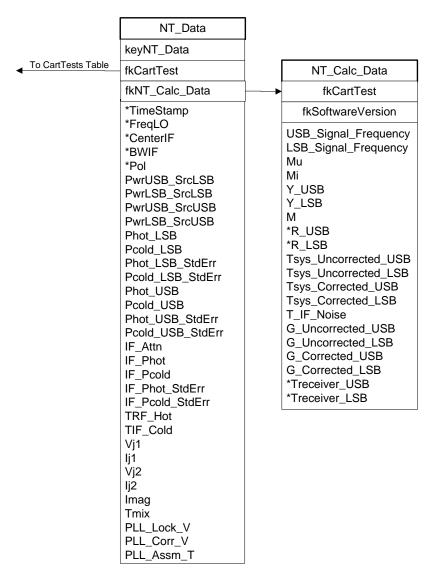


Figure 5: Cartridge Assembly Noise Temperature Test Data

3.2.2.2. <u>Cartridge Assembly Beam Pattern Test Data</u>

Raw data collected during a beam pattern scan on a cartridge assembly will be stored in the BeamPatterns and BP_Data tables. The BeamPatterns table contains general information for a single scan, while the BP_Data table contains a record for each data point at a particular XY position in a scan. Each BP_Data record contains a reference to a record in the BP_Calc_Data table, which stores the calculated values for normalized power, theta, and phi. Records in the BP_Calc_Data table will be inserted as a post-processing procedure rather than during a



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measurement. These tables are illustrated in Figure 6 with an asterisk '*' indicating the fields required for data delivery to the FEIC database for beam pattern measurements.

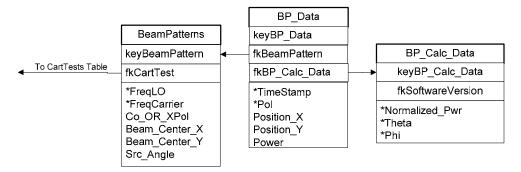


Figure 6: Cartridge Assembly Beam Pattern Data

3.2.2.3. <u>Cartridge Assembly Gain Compression Test Data</u>

Data collected during a measure of gain compression on a cartridge assembly will be stored in the GainCompression tables. This tables is illustrated in Figure 7 with an asterisk '*' indicating the fields required for data delivery to the FEIC database.

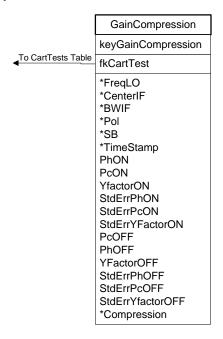


Figure 7: Cartridge Assembly Gain Compression Data



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3.3. <u>Data format of test data delivered with cartridges.</u>

The data format of operating and test data delivered with cartridges is given in [AD01]. SQL queries or software programs will be developed that extract data from the tables in the Band 6 database and format it for delivery to the FEIC database.